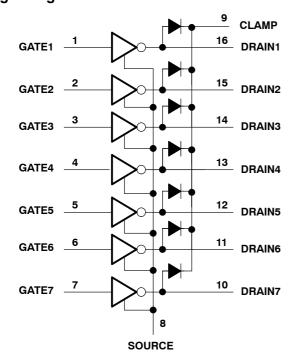
- Seven 0.5-A Independent Output Channels
- Integrated Clamp Diode With Each Output
- Low r<sub>DS(on)</sub> . . . 0.5 Ω Typical
- Output Voltage . . . 60 V
- Pulsed Current . . . 3 A Per Channel
- Avalanche Energy . . . 22 mJ

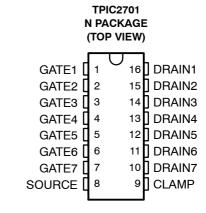
## description

The TPIC2701 is a monolithic power DMOS transistor array that consists of seven independent N-channel enhancement-mode DMOS transistors connected in a common-source configuration with open drains. The TPIC2701 is pin-for-pin functionally compatible with the Texas Instruments ULN2001A through ULN2004A.

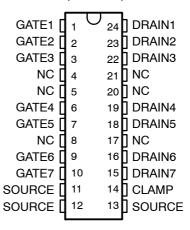
The TPIC2701 is characterized for operation over a temperature range of 0°C to 125°C.The TPIC2701M is characterized for operation over the full military temperature range of -55°C to 125°C.

## logic diagram





TPIC2701M J PACKAGE<sup>†</sup> (TOP VIEW)



NC - No internal connection

† Refer to the mechanical data for the JW package.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



## absolute maximum ratings over operating case temperature range (unless otherwise noted)

Drain-source voltage, V <sub>DS</sub>	60 V
Gate-source voltage, V <sub>GS</sub>	$\dots \dots \pm 20 \ V$
Clamp-drain voltage, V <sub>CD</sub>	60 V
Continuous source-drain diode current	0.5 A
Pulsed drain current, each output, I <sub>D</sub> (see Note 1 and Figure 17)	
Pulsed clamp current, I <sub>CL</sub> (see Note 1 and Figure 18)	3 A
Continuous drain current, each output, all outputs on	0.5 A
Single-pulse avalanche energy, E <sub>AS</sub> (see Figure 4)	22 mJ
Continuous total power dissipation	See Dissipation Rating Table
Operating virtual junction temperature range, T <sub>J</sub> : TPIC2701	–40°C to 150°C
TPIC2701M	–55°C to 150°C
Operating case temperature range, T <sub>C:</sub> TPIC2701	40°C to 125°C
TPIC2701M	–55°C to 125°C
Storage temperature range, T <sub>stq</sub>	65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: N Package .	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: J Package	300°C
E 1: Pulse duration = 10 ms, duty cycle = 6%.	

## **DISSIPATION RATING TABLE**

PACKAGE	T <sub>A</sub> ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 85°C POWER RATING	T <sub>A</sub> = 125°C POWER RATING
J	2660 mW	21.3 mW/°C	1701 mW	1382 mW	530 mW
N	1400 mW	11.0 mW/°C	905 mW	740 mW	300 mW

## electrical characteristics, T<sub>C</sub> = 25°C (unless otherwise noted)

	DADAMETED	TEST CONDITIO		Т	PIC2701		LINIT
	PARAMETER	TEST CONDITION	INS	MIN	TYP	MAX	UNIT
V <sub>(BR)DS</sub>	Drain-source breakdown voltage	$I_D = 1 \mu A$ , $V_{GS} = 0$		60			V
$V_{TGS}$	Gate-source threshold voltage	$I_D = 1 \text{ mA}, \qquad V_{DS} = V_{GS}$		1.2	1.75	2.4	V
V <sub>DS(on)</sub>	Drain-source on-state voltage	I <sub>D</sub> = 0.5 A, V <sub>GS</sub> = 15 V, See Notes 2 and 3		0.25	0.4	<b>V</b>	
	To a control of the c	V 40 V V 0	T <sub>C</sub> = 25°C		0.05	1	•
I <sub>DSS</sub>	Zero-gate-voltage drain current	$V_{DS} = 48 \text{ V},  V_{GS} = 0$	T <sub>C</sub> = 125°C		0.5	10	μ <b>A</b>
I <sub>GSSF</sub>	Forward gate current, drain short circuited to source	$V_{GS} = 20 \text{ V},  V_{DS} = 0$			10	100	nA
I <sub>GSSR</sub>	Reverse gate current, drain short circuited to source	$V_{GS} = -20 \text{ V},  V_{DS} = 0$			10	100	nA
		$V_{GS} = 15 \text{ V},  I_D = 0.5 \text{ A},$	T <sub>C</sub> = 25°C		0.5	8.0	
r <sub>DS(on)</sub>	Forward drain-source on-state resistance	See Notes 2 and 3 and Figures 5 and 6	T <sub>C</sub> = 125°C		0.8	1.3	Ω
g <sub>fs</sub>	Forward transconductance	$V_{DS}$ = 15 V, $I_D$ = 0.5 A, See Notes 2 and 3		0.5	0.8		S
C <sub>iss</sub>	Short-circuit input capacitance, common source				105		
Coss	Short-circuit output capacitance, common source	V 25 V V 0	$V_{DS} = 25 \text{ V},  V_{GS} = 0,  f = 300 \text{ kHz}$		65		рF
C <sub>rss</sub>	Short-circuit reverse transfer capacitance, common source	VDS - 20 V, VGS = 0,	1 – 500 KI IZ	•	15		p⊢

NOTES: 2. Technique should limit  $T_J$  –  $T_C$  to  $10^{\circ}C$  maximum.

3. These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts with a single output transistor conducting.



# electrical characteristics over case temperature operating range (unless otherwise noted) (see Note 4)

	DADAMETED	<b></b>	UDITIONS	- +	TP	IC2701	М	
	PARAMETER	I EST CO	NDITIONS	T <sub>C</sub> <sup>†</sup>	MIN	TYP	MAX	UNIT
,	Due:- to serve baselide	$I_D = 1 \mu A$ ,	V <sub>GS</sub> = 0	25°C	60			\ <u>/</u>
V <sub>(BR)DS</sub>	Drain-to-source breakdown voltage	$I_D = 1 \text{ mA},$	V <sub>GS</sub> = 0	Full range	60			٧
$V_{TGS}$	Gate-to-source input threshold voltage	$I_D = 1 \text{ mA},$	$V_{DS} = V_{GS}$	Full range	1.2	1.75	2.4	V
V	Decision of the state of the st		V 45V	25°C		0.25	0.45	.,
V <sub>DS(on)</sub>	Drain-to-source on-state voltage	$I_{D} = 0.5 A,$	$V_{GS} = 15 V$	Full range			0.65	V
		.,	٠, ٠	25°C		0.05	1	
I <sub>DSS</sub>	Zero-gate-voltage drain current	$V_{DS} = 48 V$ ,	$V_{GS} = 0$	Full range			10	μΑ
	Forward gate current, drain short-circuited to	.,,	., .	25°C		10	100	nA
IGSSF	source	$V_{GS} = 20 \text{ V},$	$V_{DS} = 0$	Full range			10	μΑ
	Reverse gate current, drain short-circuited to	.,,	., .	25°C		10	100	nA
IGSSR	source	$V_{GS} = -20 \text{ V},$	$V_{DS} = 0$	Full range			10	μΑ
				25°C		0.5	0.9	
r <sub>DS(on)</sub>	Forward drain-source on-state resistance	$V_{GS} = 15 V$ ,	$I_D = 0.5 A$	Full range			1.3	Ω
g <sub>fs</sub>	Forward transconductance	V <sub>DS</sub> = 15 V,	I <sub>D</sub> = 0.5 A	25°C		0.8		S
C <sub>iss</sub>	Short-circuit input capacitance, common source					105		
C <sub>oss</sub>	Short-circuit output capacitance, common source	V <sub>DS</sub> = 25 V,	$V_{GS} = 0$ ,	Full ropes		65		
C <sub>rss</sub>	Short-circuit reverse transfer capacitance, common source	f = 300 kHz		Full range		15		pF

<sup>†</sup> Full range is – 55°C to 125°C.

NOTE 4: Pulse testing techniques are used to maintain the virtual junction temperature as close to the case temperature as possible. Thermal effects must be taken into account separately.

## source-drain diode characteristics, $T_C = 25^{\circ}C$

PARAMETER		TEST SOMETIONS	Т			
		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{SD}$	Forward On voltage	$I_S = 0.5 \text{ A},  V_{GS} = 0$		0.9	1.4	V
t <sub>rr(SD)</sub>	Reverse-recovery time	$I_S = 0.5 \text{ A},  V_{GS} = 0,  V_{DS} = 48 \text{ V},$		165		ns
$Q_{RR}$	Total source-drain diode charge	di/dt = 25 A/μs, See Figure 1		250		nC

# source-to-drain diode characteristics over operating case temperature range (unless otherwise noted) (see Note 4)

DADAMETED		TEO	TEST CONDITIONS			TPIC2701M			
	PARAMETER	IES	MIN	TYP	MAX	UNIT			
$V_{SD}$	Forward On voltage	I <sub>S</sub> = 0.5 A,	V <sub>GS</sub> = 0			0.9	1.4	V	
t <sub>rr</sub>	Reverse recovery time	I <sub>S</sub> = 0.5 A,	V <sub>GS</sub> = 0,	V <sub>DS</sub> = 48 V,		165		ns	
$Q_{RR}$	Total source-to-drain diode charge	di/dt = 25 A/μs,	$T_C = 25^{\circ}C$ ,	See Figure 1		250		nC	

NOTE 4: Pulse testing techniques are used to maintain the virtual junction temperature as close to the case temperature as possible. Thermal effects must be taken into account separately.



## clamp diode characteristics, T<sub>C</sub> = 25°C

	DADAMETED	TEST SOUDITIONS	T		UNIT	
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V <sub>F</sub>	Forward on-voltage	I <sub>F</sub> = 0.5 A		1	1.5	V
$V_{BR}$	Breakdown voltage	$I_R = 1 \mu A$	60			٧
$I_R$	Reverse leakage current	V <sub>R</sub> = 48 V		0.05	1	μΑ
t <sub>rr(CD)</sub>	Reverse-recovery time	I <sub>F</sub> = 0.1 A, di/dt = 25 A/μs,		90		ns
$Q_{RR}$	Total source-drain diode charge	V <sub>CD</sub> = 48 V, See Figure 1		100		nC

# clamp diode characteristics over operating case temperature range (unless otherwise noted) (see Note 4)

	PARAMETER		TEST CONDITIONS			TPIC2701M			
						TYP	MAX	UNIT	
$V_{F}$	Forward voltage	I <sub>F</sub> = 0.5 A				1	1.5	V	
V	Drookdown voltogo	$I_R = 1 \mu A$ ,	$T_C = 25^{\circ}C$		60			٧	
$V_{(BR)}$	Breakdown voltage	I <sub>R</sub> = 1 mA	60			V			
1.	Daviene lealings arment	V 40.V	$T_C = 25^{\circ}C$			0.05	1	4	
IR	Reverse leakage current	V <sub>R</sub> = 48 V					10	μΑ	
t <sub>rr(SD)</sub>	Reverse recovery time, source-to-drain	l <sub>F</sub> = 0.1 A,	di/dt = 25 A/μs,	T <sub>C</sub> = 25°C		90		ns	
$Q_{RR}$	Total source-to-drain diode charge	$V_{CD} = 48 \text{ V},$	See Figure 1			100		nC	

NOTE 4: Pulse testing techniques are used to maintain the virtual junction temperature as close to the case temperature as possible. Thermal effects must be taken into account separately.

## resistive-load switching characteristics, $T_C = 25^{\circ}C$

DADAMETED		TEST CONDITIONS			TI			
	PARAMETER		MIN	TYP	MAX	UNIT		
t <sub>d(on)</sub>	Turn-on delay time					10		
t <sub>d(off)</sub>	Turn-off delay time	V <sub>DD</sub> = 25 V,	V, $R_L = 100 \Omega$ , s, See Figure 2	$t_{en} = 10 \text{ ns},$		30		
t <sub>r</sub>	Rise time	t <sub>dis</sub> = 10 ns,				15		ns
t <sub>f</sub>	Fall time					5		
$Q_g$	Total gate charge					2.8	3.6	
Q <sub>gs</sub>	Gate-source charge	V <sub>DS</sub> = 48 V, See Figure 3	$I_D = 0.25 A,$	$V_{GS} = 10 \text{ V},$		1.6	2	nC
$Q_{gd}$	Gate-drain charge	Goo i iguio o				1.2	1.6	

# resistive-load switching characteristics over operating case temperature range (unless otherwise noted) (see Note 4)

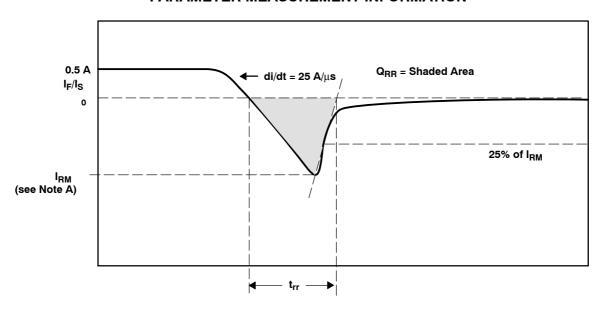
	DADAMETED		TEST CONDITIONS			TPIC2701M			
	PARAMETER		MIN	TYP	MAX	UNIT			
t <sub>d(on)</sub>	Turn-on delay time				10				
t <sub>d(off)</sub>	Turn-off delay time	V <sub>DD</sub> = 25 V,	$R_L = 100 \Omega$ , See Figure 2	$t_{en} = 10 \text{ ns},$	30				
t <sub>r</sub>	Rise time	t <sub>dis</sub> = 10 ns,				15		ns	
t <sub>f</sub>	Fall time					5			
$Q_g$	Total gate charge					2.8			
Q <sub>gs</sub>	Gate-to-source charge	V <sub>DS</sub> = 48 V, See Figure 3	$I_D = 0.25 A,$	$V_{GS} = 10 \text{ V},$		1.6		nC	
Q <sub>gd</sub>	Gate-to-drain charge	garoo				1.2			

NOTE 4: Pulse testing techniques are used to maintain the virtual junction temperature as close to the case temperature as possible. Thermal effects must be taken into account separately.

#### thermal resistance

	PARAMETER	TEST CONDITIONS MIN TYP MAX					
_	lunction to problem the areal assistance	N package with all outputs at equal power			90	0000	
$R_{ heta JA}$ Junction-to-ambient thermal resistance		J package with all outputs at equal power	66			°C/W	

## PARAMETER MEASUREMENT INFORMATION



NOTE A: I<sub>RM</sub> = maximum recovery current

Figure 1. Reverse-Recovery-Current Waveforms of Source-Drain and Clamp Diodes

## PARAMETER MEASUREMENT INFORMATION

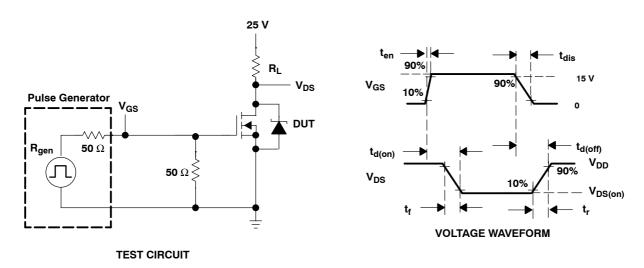


Figure 2. Resistive Switching

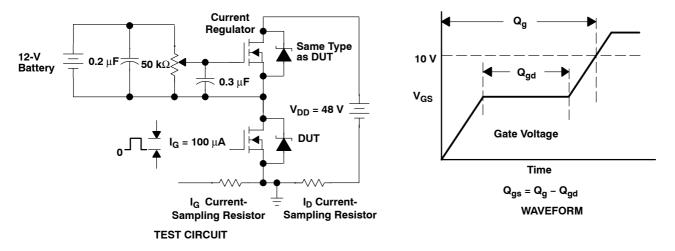
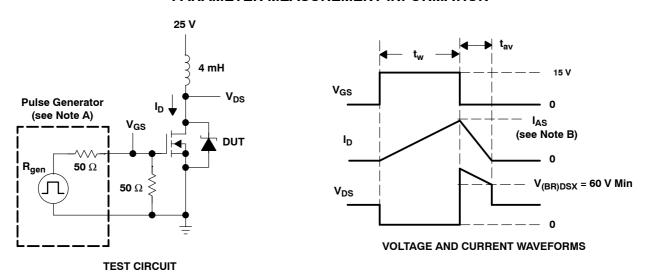


Figure 3. Gate Charge Test Circuit and Waveform

## PARAMETER MEASUREMENT INFORMATION



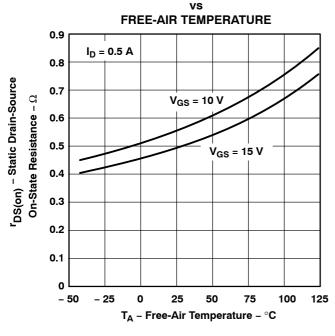
NOTES: A. The pulse generator has the following characteristics:  $t_r \le 10$  ns,  $t_f \le 10$  ns,  $Z_O = 50 \ \Omega$ .

B. Input pulse duration  $(t_w)$  is increased until peak current  $I_{AS} = 2.5 A$ .

Energy test level is defined as 
$$E_{AS} = \frac{I_{AS} \times V_{(BR)DSX} \times t_{av}}{2} = 22 \text{ mJ min.}$$

Figure 4. Single-Pulse Avalanche Energy Test Circuit and Waveforms

## STATIC DRAIN-SOURCE ON-STATE RESISTANCE



## Figure 5

**DISTRIBUTION OF** 

# FORWARD TRANSCONDUCTANCE 15 T<sub>A</sub> = 25°C I<sub>D</sub> = 0.5 A V<sub>DS</sub> = 15 V 8 0.76 0.775 0.79 0.805 0.82

Figure 7

g<sub>fs</sub> - Forward Transconductance - S

## STATIC DRAIN-SOURCE ON-STATE RESISTANCE

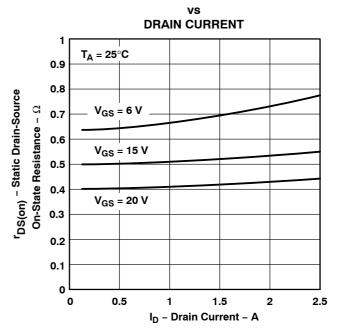


Figure 6

# DRAIN-TO-SOURCE CURRENT VS

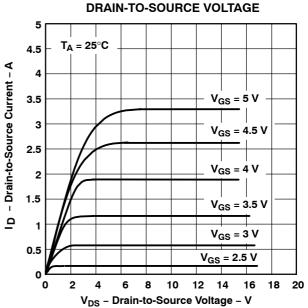


Figure 8



## GATE-SOURCE THRESHOLD VOLTAGE

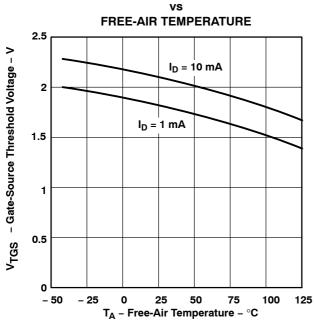


Figure 9

## SOURCE-TO-DRAIN DIODE CURRENT vs SOURCE-TO-DRAIN DIODE VOLTAGE

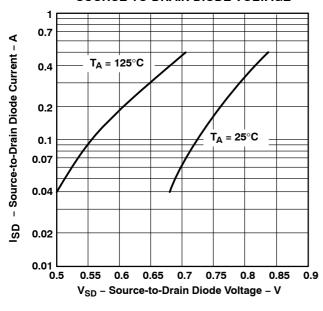


Figure 11

# GATE-SOURCE VOLTAGE vs

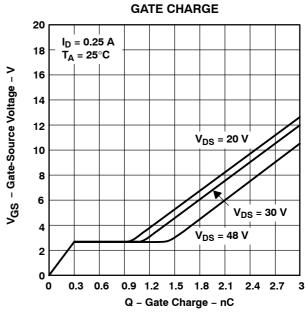


Figure 10

# SOURCE-TO-DRAIN DIODE CURRENT vs SOURCE-TO-DRAIN DIODE VOLTAGE

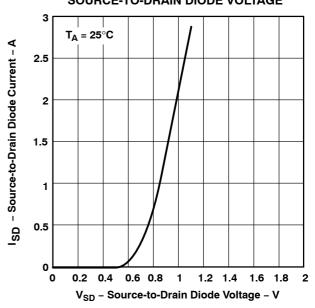
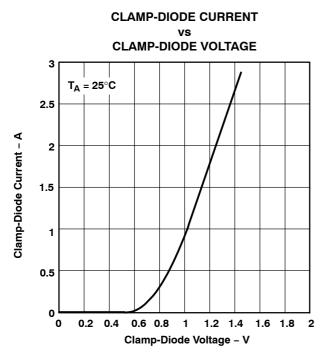


Figure 12



**CLAMP-DIODE REVERSE RECOVERY TIME** REVERSE di/dt 140 t<sub>rr</sub> - Clamp-Diode Reverse Recovery Time - ns  $I_F = 0.1 A$ 130 V<sub>R</sub> = 48 V T<sub>A</sub> = 25°C 120 110 100 90 80 70 60 50 40 30 20 30 40 50 60 70 80 100 Reverse di/dt – A/ $\mu$ s

Figure 13

Figure 14

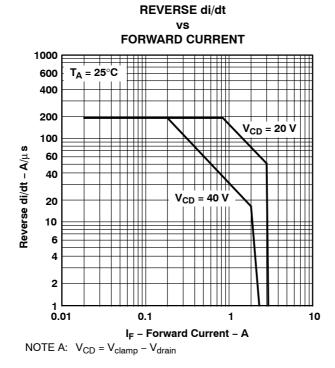


Figure 15



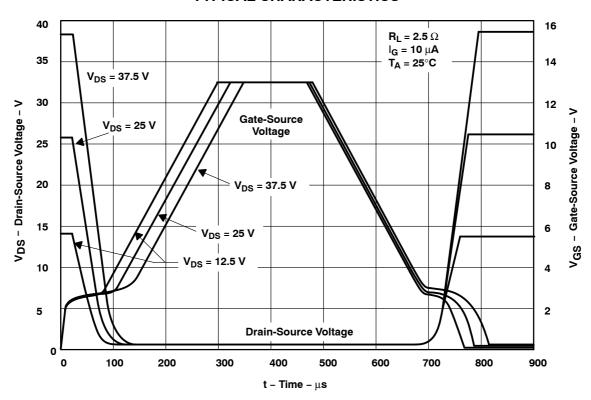
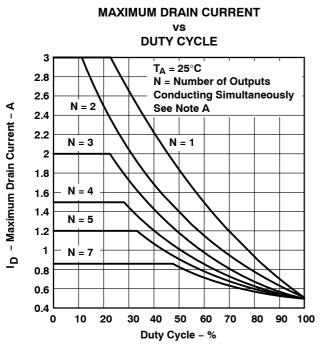


Figure 16. Resistive Switching Waveforms

## THERMAL INFORMATION



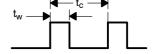
**MAXIMUM CLAMP-DIODE CURRENT DUTY CYCLE** 3 N = 1 T<sub>A</sub> = 25°C 2.8 <sub>CL</sub> - Maximum Clamp-Diode Current - A N = Number of Outputs 2.6 **Conducting Simultaneously** See Note A 2.4 2.2 2 1.8 N = 21.6 1.4 1.2 N = 31 N = 40.8 N = 50.6 0.4 0.2 70 10 20 30 40 50 60 80 0 90 100

Figure 17

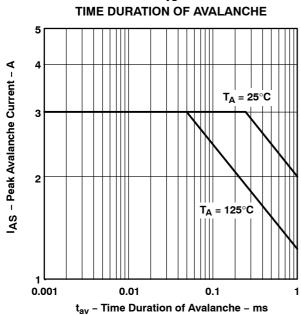
Figure 18

**Duty Cycle - %** 

NOTE A: For Figures 17 and 18,  $d = t_w/t_c = 10 \text{ ms} / t_c$ , where  $t_w$  and  $t_c$  are defined by the following:







# MAXIMUM DRAIN CURRENT vs

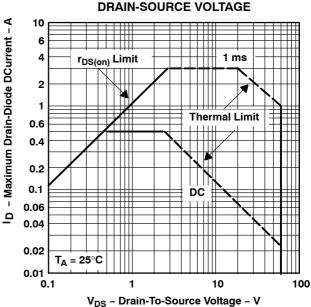


Figure 19

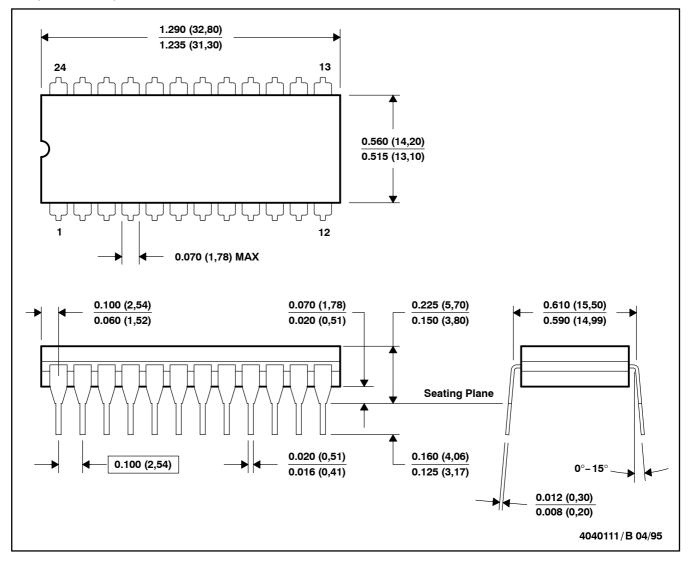
Figure 20



## **MECHANICAL INFORMATION**

## JW (R-GDIP-T24)

## **CERAMIC DUAL-IN-LINE PACKAGE**



NOTES: A. All linear dimensions are in inches (millimeters).

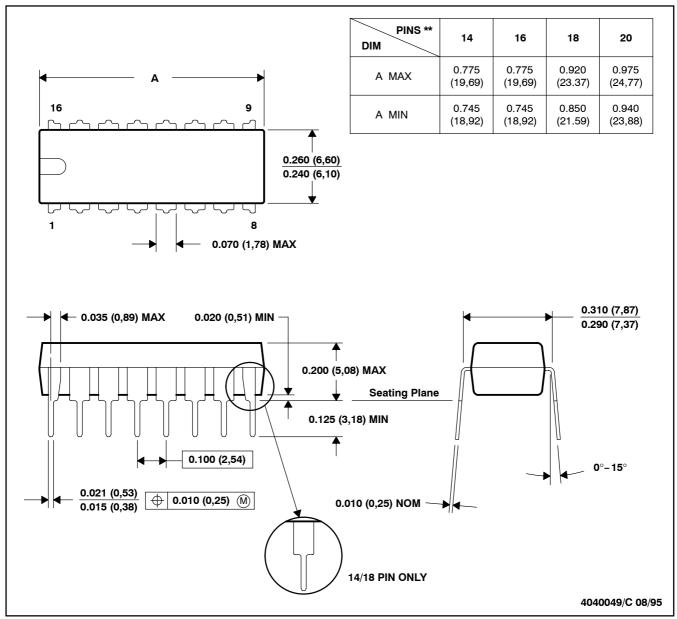
- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only
- E. Falls within MIL-STD-1835 GDIP5-T24

## **MECHANICAL INFORMATION**

## N (R-PDIP-T\*\*)

## **16 PIN SHOWN**

## PLASTIC DUAL-IN-LINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-001 (20 pin package is shorter then MS-001.)





## PACKAGE OPTION ADDENDUM

26-Mar-2007

## **PACKAGING INFORMATION**

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins Package Qty	Eco Plan <sup>(2)</sup>	Lead/Ball Finish	MSL Peak Temp <sup>(3)</sup>
TPIC2701MJB	OBSOLETE	CDIP	J	24	TBD	Call TI	Call TI
TPIC2701N	OBSOLETE	PDIP	N	16	TBD	Call TI	Call TI

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

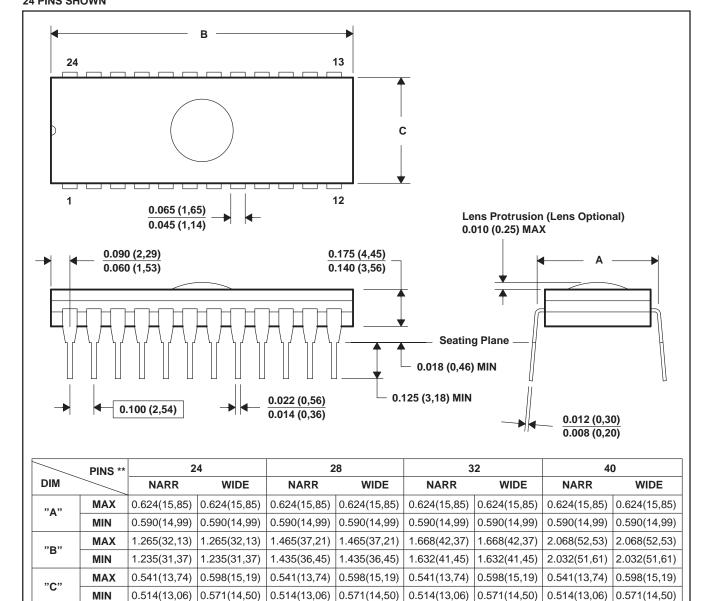
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

4040084/C 10/97

## J (R-GDIP-T\*\*)

## 24 PINS SHOWN

## **CERAMIC DUAL-IN-LINE PACKAGE**



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Window (lens) added to this group of packages (24-, 28-, 32-, 40-pin).
- D. This package can be hermetically sealed with a ceramic lid using glass frit.
- E. Index point is provided on cap for terminal identification.



# N (R-PDIP-T\*\*)

## PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



#### IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

TI products are not authorized for use in safety-critical applications (such as life support) where a failure of the TI product would reasonably be expected to cause severe personal injury or death, unless officers of the parties have executed an agreement specifically governing such use. Buyers represent that they have all necessary expertise in the safety and regulatory ramifications of their applications, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of TI products in such safety-critical applications, notwithstanding any applications-related information or support that may be provided by TI. Further, Buyers must fully indemnify TI and its representatives against any damages arising out of the use of TI products in such safety-critical applications.

TI products are neither designed nor intended for use in military/aerospace applications or environments unless the TI products are specifically designated by TI as military-grade or "enhanced plastic." Only products designated by TI as military-grade meet military specifications. Buyers acknowledge and agree that any such use of TI products which TI has not designated as military-grade is solely at the Buyer's risk, and that they are solely responsible for compliance with all legal and regulatory requirements in connection with such use.

**Applications** 

TI products are neither designed nor intended for use in automotive applications or environments unless the specific TI products are designated by TI as compliant with ISO/TS 16949 requirements. Buyers acknowledge and agree that, if they use any non-designated products in automotive applications, TI will not be responsible for any failure to meet such requirements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

**Products** 

Wireless Connectivity

#### Audio www.ti.com/audio Automotive and Transportation www.ti.com/automotive **Amplifiers** amplifier.ti.com Communications and Telecom www.ti.com/communications dataconverter.ti.com Computers and Peripherals www.ti.com/computers **Data Converters DLP® Products** www.dlp.com Consumer Electronics www.ti.com/consumer-apps DSP dsp.ti.com **Energy and Lighting** www.ti.com/energy Clocks and Timers www.ti.com/clocks Industrial www.ti.com/industrial Interface interface.ti.com Medical www.ti.com/medical Logic logic.ti.com Security www.ti.com/security Power Mgmt www.ti.com/space-avionics-defense power.ti.com Space, Avionics and Defense Microcontrollers Video and Imaging microcontroller.ti.com www.ti.com/video www.ti-rfid.com **OMAP Mobile Processors** www.ti.com/omap

TI E2E Community Home Page

www.ti.com/wirelessconnectivity

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2012, Texas Instruments Incorporated

e2e.ti.com